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|-----------------------------------|--|---|--|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination JOSEPH ET AL. | |
| | | Examiner Michelle R. Connelly-Cushwa | Art Unit 2874 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| | A | US-4,773,721 | 09-1988 | Erman et al. | 385/17 |
| * | B | US-5,317,445 | 05-1994 | DeJule et al. | 359/250 |
| | C | US-5,515,194 / | 05-1996 | Kanterakis et al. | 398/48 |
| | D | US-5,963,682 / | 10-1999 | Dorschner et al. | 385/16 |
| | E | US-6,385,376 / | 05-2002 | Bowers et al. | 385/50 |
| | F | US-6,493,483 / | 12-2002 | Gomes et al. | 385/24 |
| | G | US-6,549,691 / | 04-2003 | Street et al. | 385/18 |
| | H | US-2003/0031409 A1 / | 02-2003 | Bellman et al. | 385/33 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|---------------|----------------|
| | N | JP 04009823 A / | 01-1992 | Japan | TANAKA et al. | G02F 01/313 |
| | O | JP 59050689 A / | 03-1984 | Japan | TAKAI et al. | H04Q 03/52 |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|--|
| * | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | |
| | U | |
| | V | |
| | W | |
| | X | |

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